



ALC '09

7th International Symposium on Atomic Level Characterizations for New Materials and Devices '09

December 6(Sun) – 11(Fri), 2009

The Westin Maui Resort & Spa, Maui, Hawaii, USA

Invited Speakers (tentative)

M.S. Altman	F. Aumayr
E. Bauer	H. Brune
U. Dahmen	H.A. Dürr
K.-H. Ernst	C.S. Fadley
H.-J. Freund	B. Garrison
R. Gauvin	T. Greber
B.J. Griffin	A. Grüneis
T. Hasebe	S. Hasegawa
H. Hibino	H. Ibach
T. Ikuta	T. Jach
O. Krivanek	H. Lichte
D. Menzel	F. Meyer zu Heringdorf
G. Mizutani	K. Morgenstern
S. Morita	T. Nakagawa
C. Oshima	H. Rose
E. Rotenberg	K. Saiki
M. Schleberger	W.-D. Schneider
M. Setou	G.A. Somorjai
S. A. Song	T. Suzuki
N. Takagi	G. Thornton
M. Tsukada	T. Uchihashi
P. Varga	J. Vickerman
M. Watanabe	W. Widdra
N. Winograd	H. Winter
T. Yasue	H.W. Yeom
H. Yurimoto	

Scientific Topics

- 1. Fundamental Phenomena**
 - electron/ion-solid interactions
 - emission phenomena of light, electrons and ions
- 2. Characterization by Electrons / Ions / Infrared / Ultraviolet / X-rays**
 - AES / XPS / XPED / EPMA / ISS / MEIS / RBS / IR / etc.
- 3. Imaging Techniques**
 - TEM / STEM / AEM / SEM / SAM / SIMS
 - SPM / REM / LEEM / PEEM / FIM / etc.
- 4. Applications for Nanotechnology**
 - nanowires / nanotubes / nanoparticles
 - solid-solid / solid-liquid interfaces
- 5. Cosmic, Terrestrial & Environmental Materials**
- 6. Special Sessions**
 - nanospectroscopy
 - graphene and related materials
 - nanoscale 3-D element imaging
 - medical and biomaterials
 - surface imaging
- 7. Workshop**
 - new trends in SIMS technology
 - novel analyses with electron beams
- 8. Tutorials**

<http://alc.surf.nuqe.nagoya-u.ac.jp/alc09/>

Sponsored by The 141st Committee on Microbeam Analysis, Japan Society for the Promotion of Science